MSKSEMI 美森科













ESD

VS

TSS

MOV

GDT

PIFD

MMBT3906LP(MS)

Product specification





Features

- Low profile package
- Ideal for automated placement
- Complementary to MMBT3904LP(MS) (NPN).
- Power Dissipation of 200mW
- High Stability and High Reliability
- RoHS Compliant

Applications

- amplifying signal
- Electronic switch
- Oscillating circuit
- variable resistance

Appearance & Symbol

PACKAGE OUTLINE	Pin Configuration	Marking
1: Base 2: Emitter 3: Collector	Base	2A



Absolute Maximum Ratings (T=25℃ unless otherwise noted)

Parameter	Symbol	Value	Unit
Collector-Base Voltage	V _{CBO}	-40	V
Collector-Emitter Voltage	V _{CEO}	-40	V
Emitter-Base Voltage	V _{EBO}	-5	V
Collector Current - Continuous	Ic	-200	mA
Collector Power Dissipation	Pc	200	mW
Thermal Resistance From Junction to Ambient	R _{0JA}	625	°C/W
Junction Temperature	TJ	-55 to +150	°C
Junction and Storage Temperature	Tstg	-55 to +150	°C

Electrical Characteristics (T=25℃ unless otherwise noted)

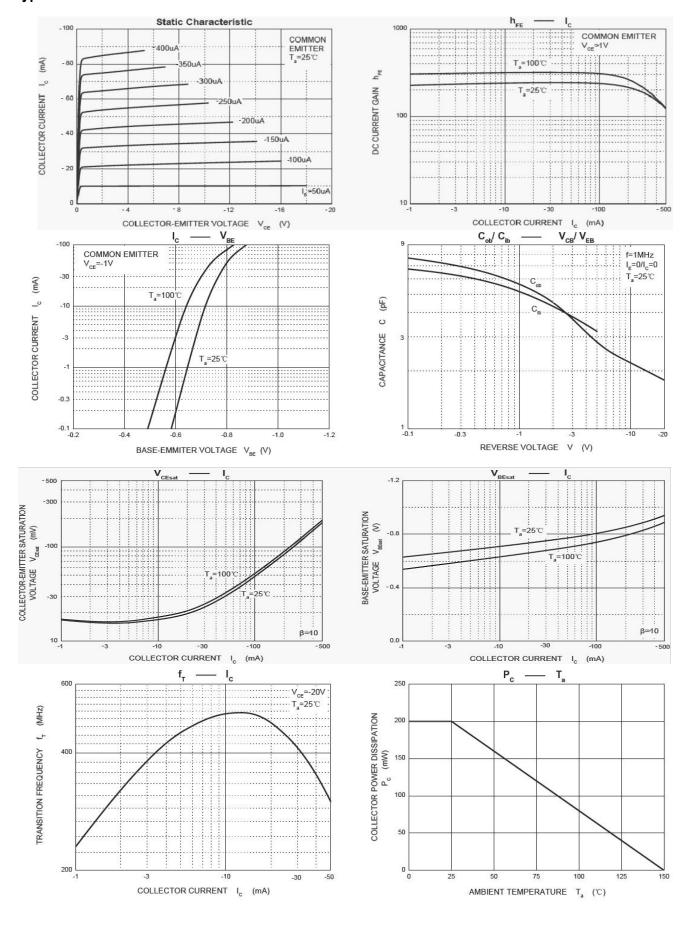
Parameter	Symbol	Test conditions	Min	Max	Unit
Collector-base breakdown voltage	V _{(BR)CBO}	I _C =-10uA, I _E =0	-40		V
Collector-emitter breakdown voltage	V _{(BR)CEO}	I _C =-1mA, I _B =0	-40		V
Emitter-base breakdown voltage	V _{(BR)EBO}	I _E =-10uA, I _C =0	-5		V
Collector cut-off current	I _{CEX}	V _{CE} =-30V, V _{BE(Off)} =-3V		-50	nA
Collector cut-off current	Ісво	V _{CB} =-40V, I _E =0		-100	nA
Emitter cut-off current	I _{EBO}	V _{EB} =-5V, I _C =0		-100	nA
	h _{FE(1)}	V _{CE} =-1V, I _C =-10mA	100	300	
DC current gain	h _{FE(2)}	V _{CE} =-1V, I _C =-50mA	60		
	h _{FE(3)}	V _{CE} =-2V, I _C =-100mA	30		
Collector-emitter saturation voltage	V _{CE(sat)}	I _C =-50mA, I _B =-5mA		-0.3	V
Base -emitter saturation voltage	V _{BE(sat)}	I _C =-50mA, I _B =-5mA		-0.95	V
Transition frequency	f _T	V _{CE} =-20V, I _C =-10mA,f=100MHz	300		MHz
Delay time	td	V _{CC} =-3V,V _{BE} =-0.5V		35	nS
Rise time	tr	I _C =-10mA, I _{B1} =I _{B2} =-1mA		35	nS
Storage time	ts	Vcc=-3V,Ic=-10mA		225	nS
Fall time	tf	I _{B1} =I _{B2} =-1mA		75	nS

Classification of hFE

Range	100-300
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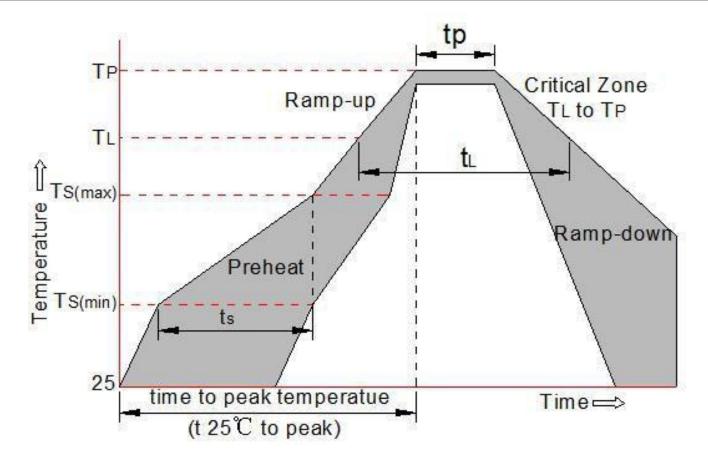
Typical Characteristics





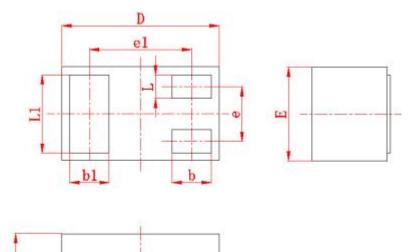
Soldering parameters

Reflow Condition		Pb-Free assembly (see as bellow)
	-Temperature Min (T _{s(min)})	+150℃
Pre Heat	-Temperature Max(T _{s(max)})	+200℃
riorioat	-Time (Min to Max) (ts)	60-180 secs.
Average	ramp up rate (Liquid us Temp (T _L) to peak)	3℃/sec. Max
	T _{s(max)} to T _L - Ramp-up Rate	
	-Temperature(T _L) (Liquid us)	+217℃
Reflow	-Temperature(t _∟)	60-150 secs.
	Peak Temp (T _p)	
Tir	me within 5℃ of actual Peak Temp (t _p)	30 secs. Max
Ramp-down Rate		6°C/sec. Max
Time 25℃ to Peak Temp (T _P)		8 min. Max
Do not exceed		+260℃



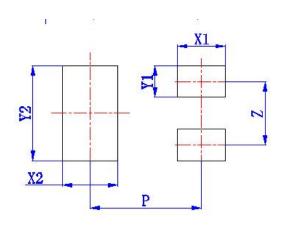


Package mechanical data



Cumbal	Millimeters		
Symbol	min	max	
А	0.4	0.5	
A1	0	0.05	
D	0.9	1.1	
E	0.55	0.65	
е	(0.35)		
e1	(0.65)		
b	0.2	0.3	
b1	0.2	0.3	
L	0.1 0.2		
L1	0.45 0.55		

Suggested Land Pattern



Symbol	Dimension in Millimeters	
	typ	
X1	(0.3)	
X2	(0.35)	
Y1	(0.2)	
Y2	(0.6)	
Z	(0.4)	
Р	(0.7)	

REEL SPECIFICATION

P/N	PKG	QTY
MMBT3906LP(MS)	DFN1006-3	10000



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